	Tuesday, October 6								
PDT	EDT	Paris	Session	Presentation / Speaker					
6:30 AM	9:30 AM	3:30 PM	36331011						
6:45 AM	9:45 AM	3:45 PM	Exhibitor Breakfast - EPC SPACE						
7:00 AM	10:00 AM	4:00 PM	Opening Remarks - David Hansen, Single Event Effects (SEE) General Chair SEE Track Introduction - Megan Casey, SEE Technical Chair						
7:15 AM	10:15 AM	4:15 PM		SEEMS - A New Facility for Single Event Effects Testing and Muon Spectroscopy  Bernard Riemer, Oak Ridge National Laboratory					
7:30 AM	10:30 AM	4:30 PM	Facilities	The LANSCE Facility for Measurement of Neutron-induced Failure in Semiconductor Devices Stephen Wender, Los Alamas National Laboratory					
7:45 AM	10:45 AM	4:45 PM		Radiation Effects Facility at Crocker Nuclear Laboratory Eric Prebys, University of CA Davis, Crocer Nuclear Laboratory					
8:00 AM	11:00 AM	5:00 PM		Domestic Heavy Ion Single-Event Effects Test Facilities: Needs, Current Status, and Future Jonathan Pellish, NASA Goddard Space Flight Center					
8:15 AM	11:15 AM	5:15 PM		Heavy Ion Beams from the K150 Cyclotron at TAMU Henry Clork, Cyclotron Institute at Texas A&M University					
8:30 AM	11:30 AM	5:30 PM		Live Q&A for Facilities Session Speakers Moderated by: Megan Casey					
8:45 AM	11:45 AM	5:45 PM		Exhibitor Break - STAR DUNDEE					
9:00 AM	12:00 PM	6:00 PM							
9:15 AM	12:15 PM	6:15 PM		Artificial Intelligence (AI) Journeys to Space					
9:30 AM	12:30 PM	6:30 PM	Invited Tutorial #1	Paul Armijo and George Williams, GSI Technology					
9:45 AM	12:45 PM	6:45 PM		(40 Minute Duration, 5 Minute Q&A Moderated by Megan Cosey)					
10:00 AM 10:15 AM	1:00 PM 1:15 PM	7:00 PM 7:15 PM	Exhibitor Break - MENTOR, A SIEMENS BUSINESS						
10:30 AM	1:30 PM	7:30 PM	Military and Aerospace Programmable Logic Devices (MAPLD) Opening Remarks - Gregory Allen, MAPLD General Chair MAPLD Track Introduction - Nadio Rezzak / Pierre Maillard, MAPLD Technical Chairs						
10:45 AM	1:45 PM	7:45 PM		Heavy Ion and Proton Induced Single Event Effects on Microchip RT PolarFire FPGA Nodio Rezzok, Microchip Technology, Inc.					
11:00 AM	2:00 PM	8:00 PM	FPGAs / SoCs,	Architecture and Radiation Advantage of Advanced FD-SOI FPGAs Melonie Berg. Space R2, LLC / Lattice Semiconductor					
11:15 AM	2:15 PM	8:15 PM	PLDs, and New Devices	Still Latched-up After All These Years: More Clues in the 7-Series FPGA Micro-Latchup Mystery Gory Swift, Swift Engineering & Rodiotion Services, LLC.					
11:30 AM	2:30 PM	8:30 PM		Live Q&A for FPGAs / SoCs, PLDs, and New Devices Session Speakers Moderated by: Nadia Rezzak, Pierre Maillard					
11:45 AM	2:45 PM	8:45 PM	Exhibitor Break - INTEGRA TECH						
12:00 PM	3:00 PM	9:00 PM							
12:15 PM	3:15 PM	9:15 PM	Panel Discussion:	Panelist 1: Paul Quintana, Microchip Technology, Inc.					
12:30 PM	3:30 PM	9:30 PM	Supply Chain Risk	Panelist 2 (Live): John Latimer, Xilinx, Inc.					
12:45 PM	3:45 PM	9:45 PM	Management	<b>Live Q&amp;A</b> Moderated by: Nadia Rezzak, Pierre Maillard					
1:00 PM	4:00 PM	10:00 PM	Mitigation of	Fault Injection to Verify Functional Safety Logic Joe Mallett, Synopsys					
1:15 PM	4:15 PM	10:15 PM	Single Event Effects in	Rethinking Your Approach to Radiation Mitigation Jacob Wiltgen, Mentor - A Siemens Business					
1:30 PM	4:30 PM	10:30 PM	FPGAs/SoCs, PLDs and	Implementing Temporal Mitigation Solutions in FPGAs Komesh Romoni, Mentor - A Siemens Business					
1:45 PM	4:45 PM	10:45 PM	Commercial Electronics	SpaceFibre for FPGA: IPs and RTG4 Radiation Test Results Alberto Gonzolez, STAR-Dundee, Ltd.					
2:00 PM	5:00 PM	11:00 PM		Live Q&A for Mitigation of Single Event Effects in FPGAs/SoCs, PLDs and Commercial Electronics Session Moderated by: Nadia Rezzak, Pierre Maillard					
2:15 PM	5:15 PM	11:15 PM							
2:30 PM	5:30 PM	11:30 PM	Exhibitor Reception						
2:45 PM	5:45 PM	11:45 PM	All attendees are invited to join us and welcome all of our 2020 Supporters and Exhibitors!						
3:00 PM	6:00 PM	12:00 AM	Also available: Technical   Social Meeting Rooms:  Collaboration Conner  SEE Beam-Off  Design This / Verify That  Students and Voung-Porjessionals Lounge  Combo Special						
3:15 PM	6:15 PM	12:15 AM							
3:30 PM	6:30 PM	12:30 AM							
3:45 PM	6:45 PM	12:45 AM	End of Tuesday Workshop Events						

	Wednesday, October 7							
PDT	EDT	Paris	Session	Presentation / Speaker				
6:30 AM	9:30 AM	3:30 PM		Exhibitor Breakfast - ASAP-1 ULTRA TEC				
6:45 AM	9:45 AM	3:45 PM						
7:00 AM 7:15 AM	10:00 AM 10:15 AM	4:00 PM 4:15 PM		Discrete Binning Analysis of Single Event Transient Pulse Width for Rate Calculations				
7:30 AM	10:30 AM	4:30 PM		Michael Campola, NASA Goddard Space Flight Center  The Radiation Assessment Matrix (RAM): A Systematic Approach to SEE Circuit Analysis in Support of Single-Event Effects Criticality Assessment (SEECA)				
				Razvan Gaza, NASA Johnson Space Center  Low and Medium Earth-Orbit Rates Using Design-of-Experiments and Monte-Carlo Methods				
7:45 AM	10:45 AM	4:45 PM		David Hansen, Data Device Corporation				
8:00 AM	11:00 AM	5:00 PM	Systems and Error Rate	A Track-Structure Based Approach to Upset-Rate Calculations David Hansen, Data Device Corporation				
8:15 AM	11:15 AM	5:15 PM	Computation	Single-Event Effects Criticality Assessment (SEECA) Guidance for Implementation Michael Campola, NASA Goddard Space Flight Center				
8:30 AM	11:30 AM	5:30 PM		Recent Results and Current Status of the Quasi-Bessel Beam Approach for Pulsed-Laser SEE Studies  Joel Holes, U.S. Novol Research Laboratory				
8:45 AM	11:45 AM	5:45 PM		Error Rate Calculation of Functional Failures Induced by Single-Event Transients in Clock Distribution Networks Thomas Lange, IRaC Technologies / Politecnica di Torino				
9:00 AM	12:00 PM	6:00 PM		Live Q&A for Systems and Error Rate Computation Session Speakers  Moderated by: Megan Casey				
9:15 AM 9:30 AM	12:15 PM 12:30 PM	6:15 PM 6:30 PM		Exhibitor Break - EMPC				
9:45 AM	12:45 PM	6:45 PM		Analysis of Single Event Transients (SETs) using Machine Learning and Ionizing Radiation Effects Spectroscopy (IRES)  Daniel Loweless, University of Tennessee - Chattomooga				
10:00 AM	1:00 PM	7:00 PM		Novel Approach to Modeling and Prediction of Single Event Upsets at Component Level				
			Data Analysis	Ashok Alagappan, ANSYS  Data: What Are They Good For? (Absolutely)				
10:15 AM	1:15 PM	7:15 PM		Ray Ladbury, NASA Goddard Space Flight Center				
10:30 AM	1:30 PM	7:30 PM		Live Q&A for Data Analysis Session Speakers Moderated by: Megan Casey				
10:45 AM	1:45 PM	7:45 PM	Exhibitor Break - RADIATION TEST SOLUTIONS					
11:00 AM	2:00 PM	8:00 PM						
11:15 AM	2:15 PM	8:15 PM		Better FPGA Verification with Open Source VHDL Verification Methodology (OSVVM)				
11:30 AM	2:30 PM	8:30 PM	Invited Tutorial #2	Jim Lewis, SynthWorks				
11:45 AM	2:45 PM	8:45 PM		(40 Minute Duration, 5 Minute Q&A Moderated by Nadia Rezzak and Pierre Maillard)				
12:00 PM	3:00 PM	9:00 PM	Exhibitor Break - COBHAM SEMICONDUCTOR AND SPACE SOLUTIONS					
12:15 PM	3:15 PM	9:15 PM						
12:30 PM	3:30 PM	9:30 PM		Using Fault Injection to Predict the Error Rate of a Large Complex Design in a Non-Hardened SRAM-Based Xilinx 7-Series FPGA Patrick Fleming, Raytheon Space and Airborne Systems				
12:45 PM	3:45 PM	9:45 PM		Fault Tracking and Modeling in Advanced Mode Processors of Single Event Effects Matthew Cannon, Sandia National Laboratories				
1:00 PM	4:00 PM	10:00 PM	Validation and	PMPedia (Parts, Materials, and Processes) Encyclopedia: A Crowd-Sourced Space Radiation Electronics Knowledge Repository Allyson Yarbrough, The Aerospace Corporation				
1:15 PM	4:15 PM	10:15 PM	Verification of FPGAs / SoCs	Accelerating and Improving Design Reviews with Analysis Tools Jason Riddley, NASA Jet Propulsion Laboratory				
1:30 PM	4:30 PM	10:30 PM	and PLDs	Executable Specifications for Hardware Assurance of SoCs and FPGAs Alric Althoff, Tortuga Logic				
1:45 PM	4:45 PM	10:45 PM		Using Static RTL Analysis to Accelerate Satellite FPGA Verification (Live) Scott Colkins, Blue Pearl Software				
2:00 PM	5:00 PM	11:00 PM		Live Q&A for Validation and Verification of FPGAs / SoCs and PLDs Session Speakers Moderated by: Nadia Rezzak, Pierre Maillard				
2:15 PM	5:15 PM	11:15 PM		All Posters Visible & Interactive Throughout Entire Session				
2:30 PM	5:30 PM	11:30 PM		SEE Testing of Renesas Intersil Current Sense Amplifier Kiran Bernard, Renesas Electronics America Inc.				
2:45 PM	5:45 PM	11:45 PM	Poster Session	Protons, Protons Everywhere - But Where Do We Test in the U.S.?  Kenneth LaBel, Science Systems and Applications, Inc. / GSFC  Single Event Effects Characterization of Microchip Programmable Current Limiting Power Switch LX7712				
3:00 PM	6:00 PM	12:00 AM		Marco Leuenberger, Microchip Technology  Technology Evaluation for High Voltage Space Applications				
3:15 PM	6:15 PM	12:15 AM		Matt Von Thun, Cobham Advanced Electronic Solutions  Reconfigurable Image Processing Applications on FPGAs				
3:30 PM	6:30 PM	12:30 AM		Mohamed El-Hadedy, California Polytechnic University  Scrubbing and In-Orbit Re-Configuration Options for Ultra Deep Sub-Micron Space-Grade FPGAs				
				Rajan Bedi, Space Chips, LLC.  End of Workshop Events				
3:45 PM	6:45 PM	12:45 AM	End of Wednesday Workshop Events					

Thursday, October 8									
PDT EDT Paris			Session Presentation / Speaker						
6:30 AM	9:30 AM	3:30 PM		- Tresentation / Specific					
6:45 AM	9:45 AM	3:45 PM		Exhibitor Breakfast - EPC SPACE					
7:00 AM	10:00 AM	4:00 PM							
7:15 AM	10:15 AM	4:15 PM	Invited Tutorial #3	Fault-tolerance Concepts, Single Event Effects Characterization, FPGA Scrubbing, and Other Use Cases Using Industry Product Examples  Lucas Tambara, Cobham Gaisler					
7:30 AM	10:30 AM	4:30 PM							
7:45 AM	10:45 AM	4:45 PM		(40 Minute Duration, 5 Minute Q&A Moderated by Nadia Rezzak and Pierre Maillard)					
8:00 AM	11:00 AM	5:00 PM		Exhibitor Break - NORTHWESTERN MEDICINE PROTON CENTER					
8:15 AM	11:15 AM	5:15 PM		NVIDIA Jetson TX2! Radiation Report					
8:30 AM	11:30 AM	5:30 PM		Christopher Heistand, Johns Ho	opkins Applied Physics Laboratory				
8:45 AM	11:45 AM	5:45 PM	Devices	Electrical Measurement of Cell-to-Cell Variation of Critical Charge in SRAM and Sensitivity to Single-Event Upsets by Low-Energy Protons  James Cannon, University of Tennessee - Chattanaooga  Tennessee - Chattanaooga  Tennessee - Chattanaooga					
9:00 AM	12:00 PM	6:00 PM		Stuck Bits from Co-60, Electrons, Protons, and Heavy Ions Steven Guertin, NASA Jet Propulsion Laboratory					
9:15 AM	12:15 PM	6:15 PM		Live Q&A for Devices Session Speakers Moderated by: Megan Casey					
9:30 AM	12:30 PM	6:30 PM		Exhibitor Break - NASA ELECTRONIC PARTS AND PACKAGING (NEPP) PROGRAM					
9:45 AM	12:45 PM	6:45 PM		Performance Evaluation of Wide-ra	ange of AI Applications on Rasberry Pi				
10:00 AM	1:00 PM	7:00 PM		Mohamed El-Hadedy, California Polytechnic University					
10:15 AM	1:15 PM	7:15 PM	Designing with	Development and FPGA Roadmap for LEONSFT and NOEL-V Processor Models  Jan Andersson, Cobham Gaisler					
10:30 AM	1:30 PM	7:30 PM	FPGAs / SoCs and PLDs		t Chip-Level Enabling New Levels of Integration and Dependability for Avionics Systems ika Athavale, Intel Corporation				
10:45 AM	1:45 PM	7:45 PM		Towards the Use of Machine Learning to Estimate the Functional Failure Rate of Complex Circuits Thomas Lange, iRoC Technologies / Politecnico di Torina					
11:00 AM	2:00 PM	8:00 PM		Live Q&A for Designing with FPGAs / SoCs and PLDs Session Speakers Moderated by: Nadia Rezzok, Pierre Maillard					
					binars / Demos en at 11:15 AM PDT.				
11:15 AM	2:15 PM	8:15 PM		Exhibitor Webinars and Den	nos will begin at 11:30 AM PDT				
11:30 AM	2:30 PM	8:30 PM		Demo of GRSCRUB Scrubber with UltraScale FPGA and Space-Grade Processor Overview/Roadmap  Cobham Gaisler					
					Northwestern Medicine Proton Center: Everything You Need to Know				
11:45 AM	M 2:45 PM	8:45 PM			Northwestern Medicine Proton Center				
12:00 PM	3:00 PM	9:00 PM		Very High Speed SpaceFibre Interfacing and Analysis with the STAR-Ultra PCIe STAR-Dundee	Rad Hard Power Solution for the XQRKU060 Renesas				
12:15 PM	3:15 PM	9:15 PM							
12:30 PM	3:30 PM	9:30 PM		3D-PLUS New Product Overview 3D-PLUS	Radiation Transport and Effects Using NOVICE EMPC				
12:45 PM	3:45 PM	9:45 PM							
1:00 PM	4:00 PM	10:00 PM		Single Event Effect Testing using a near-IR Laser System Allied Scientific Pro	SEEMS - Neutrons and Protons for Electronics SEE Testing Oak Ridge National Laboratory				
1:15 PM	4:15 PM	10:15 PM	Exhibits Open						
1:30 PM	4:30 PM	10:30 PM		Radiation Hard Standard Cell Libraries in Advanced FinFET Technology Robust Chip	Al's Journey To Space GSI Technology				
1:45 PM	4:45 PM	10:45 PM							
2:00 PM	5:00 PM	11:00 PM		RadHard Precision and Digital Timescale Silicon Technologies	Tales From the Trenches: A Security Engineer's Perspective on SoC Weaknesses Tortuga Logic				
2:15 PM	5:15 PM	11:15 PM							
				Demo of Open Source VHDL Verification Methodology SynthWorks	An Alternative Approach to SEE Testing of GaN HEMTs  EPC Space				
2:30 PM	5:30 PM	11:30 PM							
2:45 PM	5:45 PM	11:45 PM							
3:00 PM	6:00 PM	12:00 AM		eFPGA, What's Available Now, What's Coming and What's Possible!	Is Your 'Safe' FPGA Design Safe Enough?				
3:15 PM	6:15 PM	12:15 AM		FlexLogix	Mentor, A Siemens Business				
3:30 PM	6:30 PM	12:30 AM	End of Thursday Workshop Events						